Product Name	:	PCIE-USB380,PCIE-USB340
Trade Name	:	Neousys Technology
Model Number	:	PCIE-USB380,PCIE-USB340
Applicant	:	Neousys Technology
Address	:	15F, No.868-3, Zhongzheng Rd., Zhonghe Dist., New Taipei City
		23586, Taiwan
Report Number	:	F-U070-1311-287
Issue Date	:	December 5, 2013
Applicable Standards	:	FCC Part 15, Subpart B Class B ITE
		ANSI C63.4:2009

One sample of the designated product has been tested in our laboratory and found to be in compliance with the FCC rules cited above.

Industry Canada ICES-003 Issue 5 CSA-IEC CISPR22-10 Class B ITE





NVLAP LAB CODE 200575-0

TAF 0905 FCC CAB Code TW1053 IC Code 4699A VCCI Accep. No. R-1527, C-1609, T-1441, G-10, T-1334, G-10, G-614



Central Research Technology Co. **EMC Test Laboratory** 11, Lane 41, Fushuen St., Jungshan Chiu, Taipei, Taiwan, 104, R.O.C. Tel: 886-2-25984568 Fax: 886-2-25984546

J. Y. El

(Tsun-Yu Shih/ General Manager) Date: December 5, 2013

Declaration of Conformity (DoC)

Per 47 CFR §2.1077(a) & §15.19(a)(3)

The following device is herewith confirmed to comply with Part 15 of the FCC Rules.

Product Name : PCIE-USB380,PCIE-USB340 Model No. : PCIE-USB380,PCIE-USB340



Operation is subject to the following two conditions :

- (1) This device may not cause harmful interference, and
- (2) This device must accept any interference received, including interference that may cause undesired operation.

The characteristics of electromagnetic emission has been evaluated by Central Research Technology Co. (NVLAP Lab. Code : 200575-0), and the results are shown in the test report. (Report No. : F-U070-1311-287, issued in 2013)

It is understood that each unit marketed is identical to the device as tested, and any changes to the device that could adversely affect the emission characteristics will require retest.

The following importer/manufacturer is responsible for this declaration:

Company Name :				
Company Address :				
Telephone :	_ Fax :			
The person to be responsible for marking this declaration:				
Name (Full name)	Position/Title			
Legal Signature	Date			

FCC DoC Test Report

for

PCIE-USB380,PCIE-USB340

Brand Name	:	Neousys Technology
Model No.	:	PCIE-USB380,PCIE-USB340
Report Number	:	F-U070-1311-287
Date of Receipt	:	November 26, 2013
Date of Report	:	December 5, 2013

Prepared for

Neousys Technology

15F, No.868-3, Zhongzheng Rd., Zhonghe Dist., New Taipei City 23586, Taiwan

Prepared by Central Research Technology Co. EMC Test Laboratory

11, Lane 41, Fushuen St., Jungshan Chiu, Taipei, Taiwan, 104, R.O.C.



NVLAP LAB CODE 200575-0

This report shall not be reproduced, except in full, without the written approval of Central Research Technology Co.. It may be duplicated completely in its entirely for legal use with the permission of the applicant. It should not be used to claim product endorsement by NVLAP, NIST or any U.S. government agency. The test result in the report applies only to the sample tested.

Verification of Compliance

Equipment Under Test	:	PCIE-USB380,PCIE-USB340
Model No.	:	PCIE-USB380,PCIE-USB340
Applicant	:	Neousys Technology
Address	:	15F, No.868-3, Zhongzheng Rd., Zhonghe Dist., New Taipei
		City 23586, Taiwan
Applicable Standards	:	FCC Part 15, Subpart B Class B ITE
		ANSI C63.4:2009
		Industry Canada ICES-003 Issue 5
		CSA-IEC CISPR22-10 Class B ITE
Date of Testing	:	November 27~29, 2013
Deviation	:	N/A
Condition of Test Sample	:	Engineering Sample

We, **Central Research Technology Co.**, hereby certify that one sample of the designated product was tested in our facility during the period mentioned above. The test records, data evaluation and Equipment Under Test (EUT) configurations shown in the present report are true and accurate representation of the measurements of the sample's EMC characteristics under the conditions herein specified.

The test results show that the EUT as described in the present report is in compliance with the requirements set forth in the standards mentioned above and apply to the tested sample identified in the present report only. The test report shall not be reproduced, except in its entirety, without the written approval of Central Research Technology Co.

PREPARED BY	:	Ius C	/, DATE	: Dec. 5, 2013
		(Iris Chen/System	Executive)	
APPROVED BY	:	T. Y. (Tsun-Yu Shih/Ger	DATE	: _ Dec. t, 20/3

Contents

1.	Gen	eral Description	4
	1.1	General Description of EUT	4
	1.2	Test Mode	5
	1.3	Applied standards	6
	1.4	Test Setup for the EUT	7
	1.5	The Support Units	7
	1.6	Layout of the Setup	9
	1.7	Test Capability	10
2.	Con	ducted Emission Measurement	12
	2.1	Limits for Emission Measurement	
	2.2	Test Instruments	
	2.3	Test Procedures	15
	2.4	Test Configurations	16
	2.5	Photographs of the Test Configurations	17
	2.6	Test Results	18
3.	Rad	iated Emission Measurement	20
	3.1	Limits for Emission Measurement	20
	3.2	Test Instruments	21
	3.3	Test Procedures	23
	3.4	Test Configurations	25
	3.5	Photographs of the Test Configurations	26
	3.6	Test Results	27
Att	achn	nent 1 Photographs of EUT	31
Att	achn	nent 2 Modifications of EUT	34

1. General Description

1.1 General Description of EUT

Equipment Under Test	:	PCIE-USB380,PCIE-USB340
Model No.	:	PCIE-USB380,PCIE-USB340
Power in	:	Supplied by the connected PC
Highest Operating Frequency	:	4.8GHz from the test specification
Manufacturer	:	Neousys Technology
Function Description	:	

The EUT is an engineering sample of the PCIE-USB380. Please refer to the user's manual for the details.

The I/O ports of EUT are listed below:

No.	I/O Port Type	Quantity
1	PCIe connected port	1
2	USB 3.0 port	8

1.2 Test Mode

Normal operating as the specification of manufacturer.

1.3 Applied standards

According to the specifications of the manufacturer and the requirements set in 47CFR Part 15, the applied standards to evaluate the compliance of the EUT are as following, and the measurement procedures specified in ANSI C63.4: 2009 are performed.

According to 47CFR Part 15 Section 15.33(b), the test frequency range of radiated emission measurements are listed below and the EUT herein shall be tested as:

Type of EUT	Highest frequency generated or used in the device or on which the device operates or tunes (MHz)	Upper frequency of measurement range (MHz)
	Below 1.705	30
	1.705 - 108	1000
	108 - 500	2000
	500 - 1000	5000
		5 th harmonic of the highest
\checkmark	Above 1000	frequency or 40GHz,
	115	whichever is lower

All the test items are as following:

Applied Standards	Test Items	Results
FCC Part 15, Subpart B	☑ Conducted Emission Measurement	<u>PASS</u>
Class B ITE	☑ Radiated Emission Measurement	<u>PASS</u>

1.4 Test Setup for the EUT

The EUT is an unique unit connected with other necessary accessories and support units listed in the next section. It has been tested against each standard after the following setup steps:

- a. Install the EUT inside a PC.
- b. Connect all the necessary accessories and support units to the appropriate power source.
- c. Turn on the PC and all the accessories and support units.
- d. Load an EMC test software into the PC and execute it under the Windows environment.
- e. The PC reads/ writes messages from/ to the USB 3.0 HDD by the EUT continuously.
- f. The PC sends "H" patterns to the monitor continuously.
- g. The PC sends messages to the modem.
- h. The PC sends "H" patterns to the printer, which prints them on paper.
- i. Repeat and keep the setup steps listed above before and during all tests.

EUT I/O ports / Peripherals	Exerciser Program (software)	Version of Program		
EUT				
Monitor				
Modem	BurnIn Test.exe	V 7.1		
USB 3.0 HDD				
Printer				

1.5 The Support Units

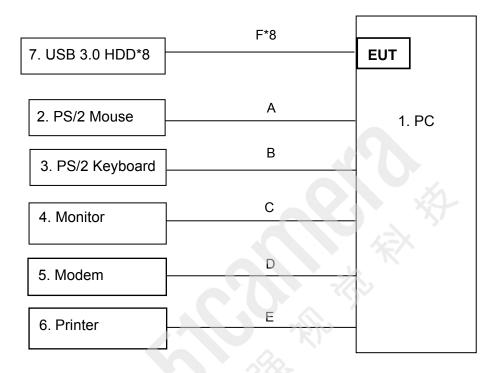
Conducted Emission Test

No.	Unit	Model No.	FCC ID	Trade Name	Power Cord	Supported by lab.
1	PC	Elite 8200 MT	DoC	HP	1.8m	\checkmark
2	PS/2 Mouse	MO71KC	DoC	DELL	N/A	\checkmark
3	PS/2 Keyboard	SK-8110	DoC	DELL	N/A	✓
4	Monitor	U2410	DoC	DELL	1.8m	✓
5	Modem	DM-1414	IFAXDM1414	ACEEX	1.8m	✓
6	Printer	LQ-300+11	N/A	EPSON	1.8m	~
7	USB 3.0 HDD	HD-PCTU3	DoC	BUFFALO	N/A	\checkmark

Radiated Emission Test

No.	Unit	Model No.	FCC ID	Trade Name	Power Cord	Supported by lab.
1	PC	Elite 8200 MT	DoC	HP	1.8m	\checkmark
2	PS/2 Mouse	MO71KC	DoC	DELL	N/A	~
3	PS/2 Keyboard	SK-8110	DoC	DELL	N/A	~
4	Monitor	U2410	DoC	DELL	1.8m	~
5	Modem	DM-1414	IFAXDM1414	ACEEX	1.8m	~
6	Printer	LQ-300+11	N/A	EPSON	1.8m	~
		My Passport Essential	DoC	WD	N/A	~
7	USB 3.0 HDD	HD-PCTU3	DoC	BUFFALO	N/A	~
		My Passport	DoC	WD	N/A	\checkmark

1.6 Layout of the Setup



Connecting Cables :

No.	Cable	Length	Shielded	Core	Shielded Backshell	Supported by lab.	Note
А	PS/2 Mouse Cable	1.8m	✓			\checkmark	
В	PS/2 Keyboard Cable	2.0m	~			\checkmark	
С	VGA Cable	1.7m	✓	\checkmark		✓	2 Cores
D	Modem Cable	1.8m	✓	\checkmark		✓	2 Cores
Е	USB Cable	1.8m	✓	\checkmark		\checkmark	2 Cores
F	USB 3.0 Cable	1.0m	\checkmark			\checkmark	

1.7 Test Capability

Test Facility

The test facility used for evaluating the conformance of the EUT with each standard in the present report meets what required in CISPR16-1-4, CISPR16-2-3 and ANSI C63.4: 2009.

Test Room	Type of Test Room	Descriptions		
TR1	10m semi-anechoic chamber ($23m \times 14m \times 9m$)	Complying with the NSA and the site VSWR requirements in documents		
TR1	3m fullly-anechoic chamber (23m × 14m × 9m)	CISPR 22 and ANSI C63.4: 2009. for the radiated emission measurement.		
TR11	3m semi-anechoic chamber (9m × 6m × 6m)	Complying with the NSA requirements in documents CISPR 22 for the radiated emission measurement.		
TR5	Shielding Room ($8m \times 5m \times 4m$)	For the conducted emission		
TR4	Shielding Room (5m×3m×3m)	measurement.		

Test Laboratory Competence Information

Central Research Technology Co. has been accredited / filed / authorized by the agencies listed in the following table.

Certificate	Nation	Agency	Code	Mark
	USA	NVLAP	200575-0	ISO/IEC 17025
	R.O.C. (Taiwan)	TAF	0905	ISO/IEC 17025
Accreditation Certificate	R.O.C. (Taiwan)	BSMI	SL2-IN-E-0033, SL2-IS-E-0033, SL2-R1/R2-E-0033, SL2-A1-E-0033, SL2-L1-E-0033	ISO/IEC 17025
	USA	FCC	474046,TW1053	Test facility list & NSA Data
Site Filing Document	Canada	IC	4699A-1,-3	Test facility list & NSA Data
	Japan	VCCI	R-1527,C-1609, C-4400, T-1441, T-1334, G-10, G-614	Test facility list & NSA Data
Authorization	Germany	TUV	10021687	ISO/IEC 17025
Certificate	Norway	Nemko	ELA 212	ISO/IEC 17025

The copy of each certificate can be downloaded from our web site: www.crc-lab.com

2. Conducted Emission Measurement

Test Result : PASS

2.1 Limits for Emission Measurement

☑ Limits for conducted disturbances at the power mains

Frequency (MHz)	Class A E	Class A Equipment		Equipment	
	Quasi-peak	Average	Quasi-peak	Average	
(1011 12)	(dBµV)	(dBµV)	(dBµV)	(dBµV)	
0.15 to 0.5	79	66	66 - 56	56 – 46	
0.5 to 5	73	60	56	46	
5 to 30	73	60	60	50	
Note 1- The lower limit shall apply at the transition frequency.					
Note 2- The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to					
0.5MHz for Cl	ass B equipment.				

2.2 Test Instruments

Test Site and	Manufacturer	Model No./	Last	Calibration	
Equipment	Manufacturer	Serial No.	Calibration Date	Due Date	
Test Receiver	R&S	ESCS 30/	Jan. 14, 2013	Jan. 14, 2014	
Test Receiver	ΓαΟ	836858/021	Jan. 14, 2013	Jan. 14, 2014	
LISN	R&S	ESH2-Z5/	March 15, 2013	March 15, 2014	
LIGIN	Γασ	880669/039		March 15, 2014	
2 nd LISN	R&S	ENV4200/	Marah 20, 2012	Marah 20, 2014	
2 LISIN	Rao	833209/010	March 29, 2013	March 29, 2014	
50Ω terminator	N/A	N/A/	Aug. 10, 2012	Aug. 10, 2014	
	IN/A	001	Aug. 19, 2013	Aug. 19, 2014	
RF Switch	R&S	RSU28/	Aug. 19, 2013	Feb. 19, 2014	
	κασ	338965/002	Aug. 19, 2013	Feb. 19, 2014	
RF Cable	N/A	N/A/	Aug. 19, 2013	Feb. 19, 2014	
RF Cable	N/A	C0052 ~ 56	Aug. 19, 2013	Feb. 19, 2014	
Test Software	Audix	e3/		NCR	
	Audix	Ver. 5.2004-2-19k	NCR	NCK	
TR5	ETS	TR5/	NCR	NCR	
shielded room	LINDGREN	15353-F	NCK	NCK	

Note:

1. The calibrations are traceable to NML/ROC.

2. NCR : No Calibration Required.

Measurement Uncertainty

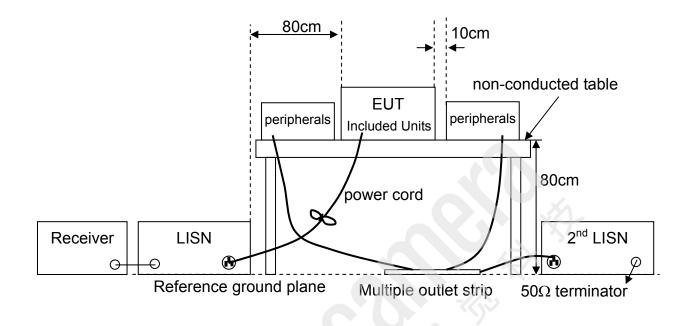
The assessed measurement uncertainty with a suitable coverage factor K to ensure 95% confidence level for the normal distribution are shown as below, the values are less than U_{cispr} in table 1 of CISPR 16-4-2.

Equipment	Model Number	Uncertainty Value
LISN	ESH2-Z5	3.0dB
LISN	ENV 4200	3.0dB

2.3 Test Procedures

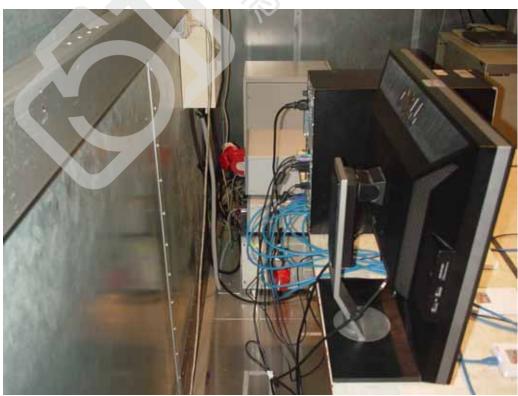
- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a non-conducted table with a height of 0.8 meters above the reference ground plane and 0.4 meters from the conducting wall of the shielded room. Also if the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 12 millimeters above the reference ground plane.
- c. Connect the EUT's power source to the appropriate power mains through the LISN.
- d. All the other peripherals are connected to the 2nd LISN, if any.
- e. The LISN was placed 0.8 meters from the EUT and at least 0.8 meters from other units and other metal planes.
- f. Measure the conducted emissions on each power line (Neutral Line and Line 1 Hot side) of the EUT's power source by using the test receiver connected to the coupling RF output port of LISN.
- g. Rapidly scan the signal from 150kHz to 30MHz by using the receiver through the Maximum-Peak detector to determine those frequencies associated with higher emission levels for each measured line.
- h. Then measure the maximum level of conducted disturbance for each frequency found from step g. by using the receiver through the Quasi-Peak and Average detectors per CISPR 16-1.
- i. Record the level for each frequency and compare with the required limit.

2.4 Test Configurations



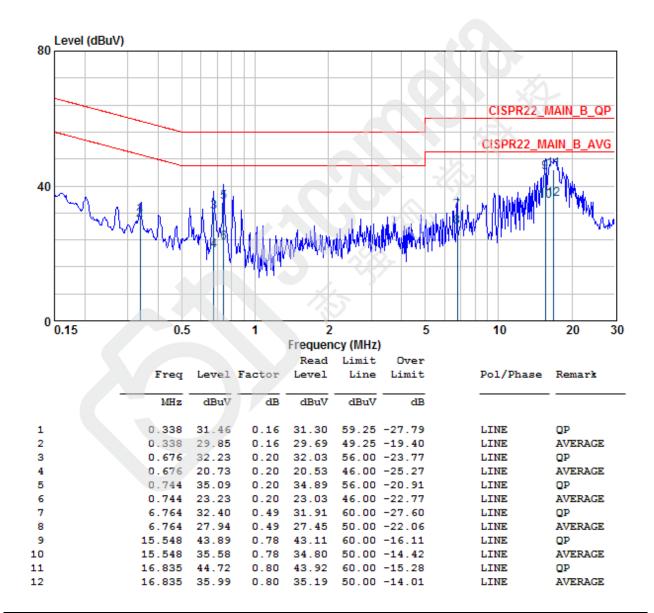


2.5 Photographs of the Test Configurations



2.6 Test Results

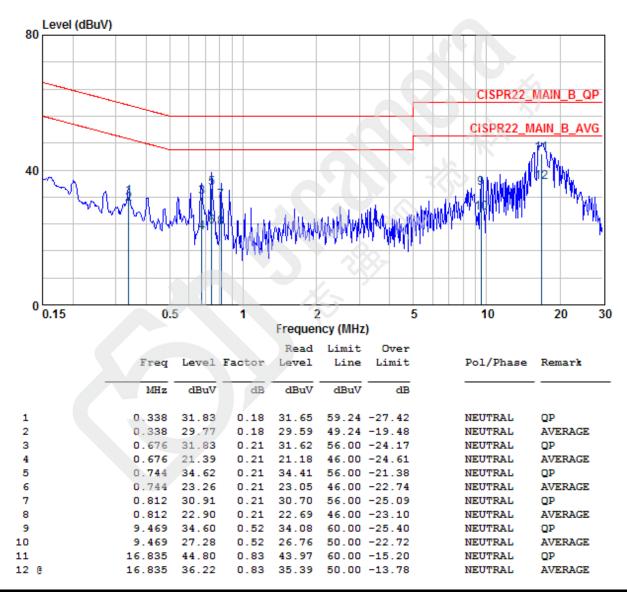
Test Mode	:	Normal			
Test Voltage	:	120V/60Hz to	120V/60Hz to the connected PC		
Tester	:	Kent	Temperature	:	27°C
Humidity	:	50%RH	Frequency Range	:	150kHz~30MHz
IF Bandwidth	:	9kHz	Phase	:	Line



Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + insertion loss of LISN.
- 3. Q.P. is abbreviation of quasi-peak.

Test Mode	:	Normal			
Test Voltage	:	120V/60Hz to	120V/60Hz to the connected PC		
Tester	:	Kent	Temperature	:	27°C
Humidity	:	50%RH	Frequency Range	:	150kHz~30MHz
IF Bandwidth	:	9kHz	Phase	:	Neutral



Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + insertion loss of LISN.
- 3. Q.P. is abbreviation of quasi-peak.

3. Radiated Emission Measurement

Test Result : PASS

3.1 Limits for Emission Measurement

☑ Limits for radiated disturbances below 1000MHz

Frequency	Class A Equipment (10m distance)	Class B Equipment (3m distance)				
(MHz)	Quasi-peak	Quasi-peak				
	(dBµV/m)	(dBµV/m)				
30 to 88	39.1	40				
88 to 216	43.5	43.5				
216 to 960	46.4					
960 to 1000	49.5	54				
Note 2- Additional pro	t shall apply at the transition frequency. visions may be required for cases where					
•	Note 3- According to 15.109(g), as an alternative to the radiated emission limits shown above, digital devices may be shown to comply with the standards (CISPR), Pub. 22 shown as below.					
30 to 230	40	30				
230 to 1000	47	37				

☑ Limits for radiated disturbances above 1000MHz at a measuring distance of 3m

Frequency	Class A Ec	Class A Equipment		quipment
Frequency (GHz)	Peak	Average	Peak	Average
(GHZ)	(dBµV/m)	(dBµV/m)	(dBµV/m)	(dBµV/m)
1 to 40	80	60	74	54

3.2 Test Instruments

☑ Below 1GHz measurement

Test Site and	Manufacturer	Model No./	Last	Calibration
Equipment		Serial No.	Calibration Date	Due Date
EMI Test Receiver	R&S	ESCS 30/ 836858/020	Sept. 9, 2013	Sept. 9, 2014
Broadband Antenna	R&S	HL-562/ 360543/007	March 27, 2013	March 27, 2014
Broadband Antenna	R&S	HL-562/ 830547/010	April 30, 2013	April 30, 2014
Pre-Amplifier	Mini Circuit	ZKL-2/ 001	July 15, 2013	Jan. 15, 2014
Pre-Amplifier	Mini Circuit	ZKL-2/ 002	July 15, 2013	Jan. 15, 2014
Spectrum Analyzer	R&S	FSP7/ 100108	August 19, 2013	August 19, 2014
Spectrum Analyzer	R&S	FSP7/ 100384	Jan. 10, 2013	Jan. 10, 2014
RF Cable	JYEBAO	0214/ C0049	July 15, 2013	Jan. 15, 2014
RF Cable	JYEBAO	0214/ C0050	July 15, 2013	Jan. 15, 2014
Test Software	Audix	e3/ Ver. 4.3.714.e	NCR	NCR
TR1 Semi - anechoic Chamber	ETS. LINDGREN	TR1/ 17627-B	May 4, 2013	May 4, 2014

Note:

1. The calibrations are traceable to NML/ROC.

- 2. NCR : No Calibration Required.
- 3. The calibration date of the chamber TR1 listed above is the date of NSA measurement.

☑ Above 1GHz measurement (TR1)

Test Site and Equipment	Manufacturer	Model No./ Serial No.		Last Calibration Date	Calibration Due Date
Horn Antenna	EMCO	3117/ 00082847		March 5, 2013	March 5, 2014
Bore-sight Antenna Mast	Sunol	TLT2/ 051110-5		NCR	NCR
	KMIC		KMA010180A01/ 99056	Oct. 17, 2013	Oct. 17, 2014
Pre-Amplifier	MITEQ	Ŋ	JS4-00101800- 28-10P/1498979	Dec. 21, 2012	Dec. 21, 2013
			JS4-00101800- 28-5A/742309	Dec. 19, 2012	Dec. 19, 2013
Spectrum Analyzer	R&S	FSP40/ 100031		July 15, 2013	July 15, 2014
RF Cable	Suhner	Sucoflex 106P / C0091 + C0092		Oct. 14, 2013	April 14, 2014
Test Software	Audix	e3/ Ver. 4.3.714.e		NCR	NCR
TR1 Fully - anechoic Chamber	ETS. LINDGREN	TR1/ 17627-B		Feb. 23, 2013	Feb. 23, 2014

Note:

- 1. The calibrations are traceable to NML/ROC.
- 2. NCR : No Calibration Required.
- 3. The calibration date of the chamber TR1 listed above is the date of site VSWR measurement.

Measurement Uncertainty

The assessed measurement uncertainty with a suitable coverage factor K to ensure 95% confidence level for the normal distribution are shown as below, the values are less than U_{cispr} in table 1 of CISPR 16-4-2.

Test Site	Polarization	Frequency Range			
(Measuring distance)		30MHz ~200MHz	200MHz ~1000MHz		
TR1(10m)	Horizontal	3.7dB	3.7dB		
	Vertical	3.5dB	3.9dB		
TR11(3m)	Horizontal	3.3dB	3.8dB		
	Vertical	4.1dB	5.1dB		

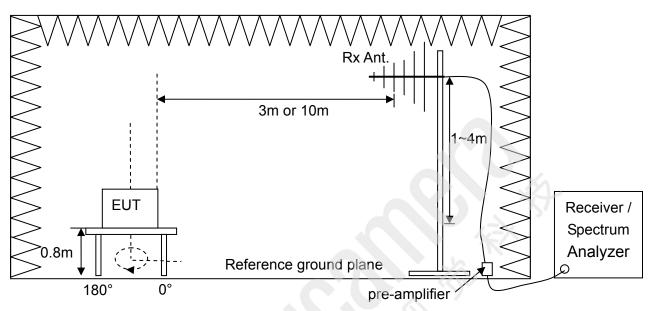
Test Site	Polarization	Frequency Range			
(Measuring distance)	T OTATIZATION	1GHz~6GHz	6GHz~18GHz		
TR1(3m)	Horizontal	4.8dB	4.9dB		
(om)	Vertical	4.8dB	4.8dB		

3.3 Test Procedures

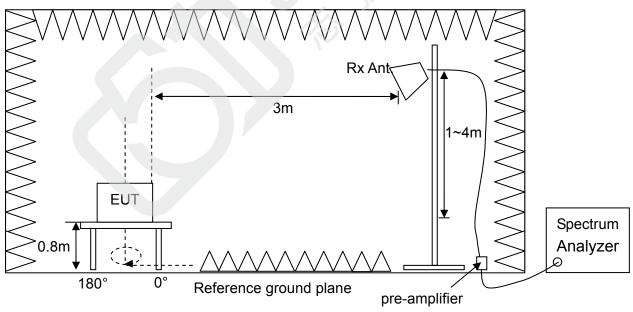
- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a non-conducted table with a height of 0.8 meters above the reference ground plane in the semi-anechoic chamber. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 12 millimeters above the reference ground plane in the semi-anechoic chamber.
- c. For the measurement of frequency below 1000MHz, the EUT was set 10m away from the interference receiving antenna for the limit of Class A equipment or CISPR 22. For Class B equipment and the measurement of frequency above 1000MHz, the EUT was set 3m away from the interference receiving antenna.
- d. Rapidly sweep the signal in the test frequency range by using the spectrum through the Maximum-peak detector.
- e. Rotate the EUT from 0° to 360° and position the receiving antenna at heights from 1 to 4 meters above the reference ground plane continuously to determine at least six frequencies associated with higher emission levels and record them.
- f. For measurement of frequency above 1000MHz, the beamwidth of receiving horn antenna should keep covering EUT when the receiving horn antenna height varied.
- g. Then measure each frequency found from step e. by using the spectrum with rotating the EUT and positioning the receiving antenna height to determine the maximum level.
- h. Finely tune the antenna and turntable around the recorded position of each frequency found from step f.
- i. For measurement of frequency below 1000MHz, set the receiver detector to be Quasi-Peak per CISPR 16-1 to find out the maximum level occurred.
- j. For measurement of frequency above 1000MHz, set the spectrum detector to be Peak or Average to find out the maximum level occurred, if any.
- k. Record frequency, azimuth angle of the turntable, height, and polarization of the receiving antenna and compare the maximum level with the required limit.
- I. Change the receiving antenna to another polarization to measure radiated emission by following step d. to k. again.
- m. If the peak emission level measured from step e. is 4dB lower than the limit specified, then the emission values presented will be the peak value only. Otherwise, accurate Q.P. value will be measured and presented.

3.4 Test Configurations

Radiated Emission Measurement below 1000MHz



Radiated Emission Measurement above 1000MHz





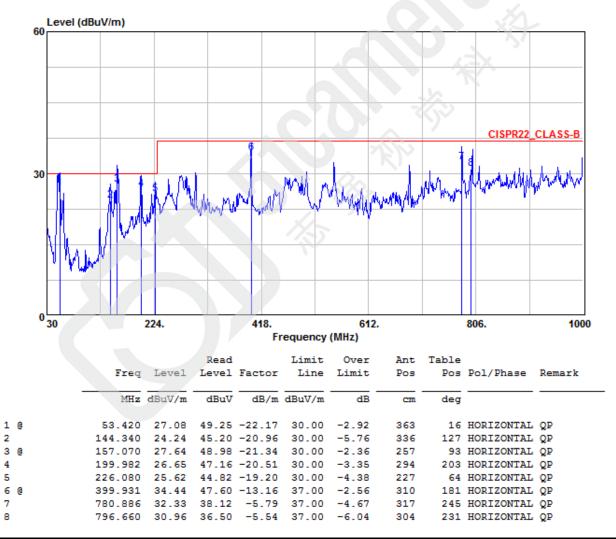
3.5 Photographs of the Test Configurations



3.6 Test Results

Radiated Emission Measurement below 1000MHz

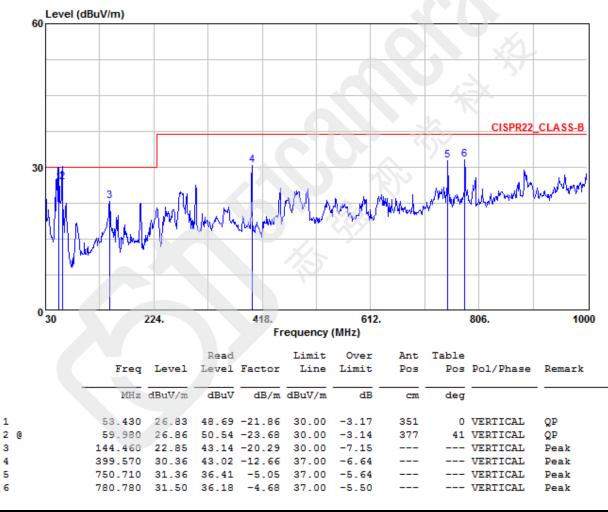
Test Mode	:	Normal			
Test Voltage	:	120V/60Hz to the connected PC			
Tester	:	Carl	Temperature	:	23°C
Humidity	:	69%RH	Frequency Range	:	30MHz~1GHz
IF Bandwidth	:	120kHz	Polarization	÷	Horizontal



Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.
- 3. Q.P is abbreviation of quasi-peak.

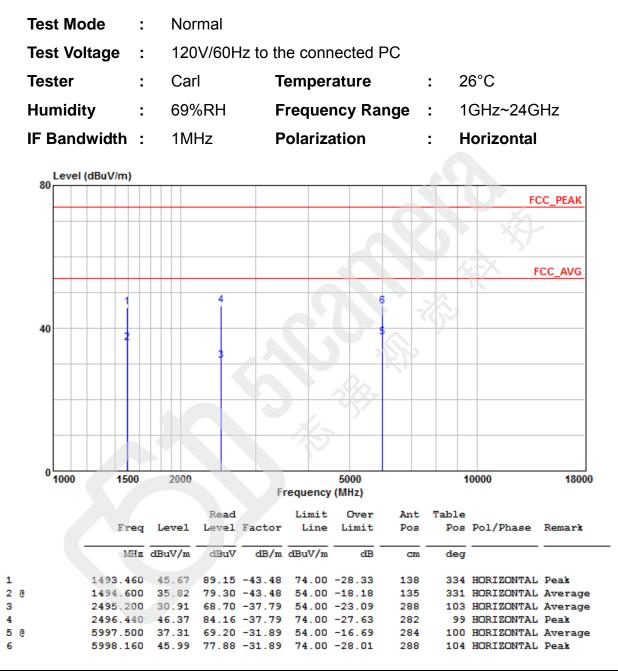
Test Mode	:	Normal			
Test Voltage	:	120V/60Hz to the connected PC			
Tester	:	Carl	Temperature	:	23°C
Humidity	:	69%RH	Frequency Range	:	30MHz~1GHz
IF Bandwidth	:	120kHz	Polarization	:	Vertical



Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.
- 3. Q.P is abbreviation of quasi-peak.

Radiated Emission Measurement above 1000MHz

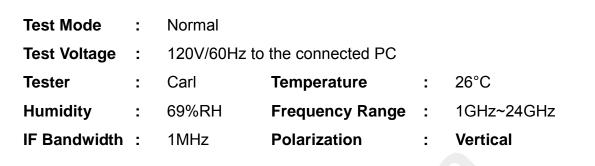


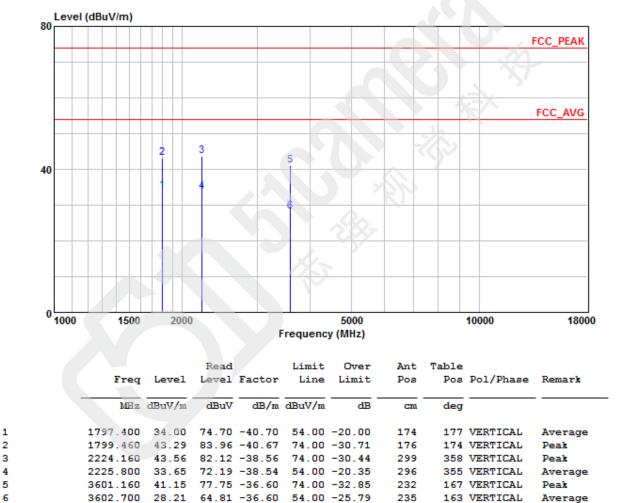
Note:

1. Emission Level = reading value + correction factor.

2. Correction factor = cable loss + antenna factor – gain of pre-amplifier.

No signal can be detected from 18GHz to 25GHz, so the graphs are omitted above 18GHz.





Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.

No signal can be detected from 18GHz to 25GHz, so the graphs are omitted above 18GHz.

Attachment 1

Photographs of EUT







Attachment 2

Modifications of EUT

Statement of the EUT Modifications

According to the rules of ANSI C63.4-2009 clause 10.2.13, the following equipment (EUT):

Equipment Under Test :	:	PCIE-USB380,PCIE-USB340
Model No.	:	PCIE-USB380,PCIE-USB340
Applicant :	:	Neousys Technology
Address :	•	15F, No.868-3, Zhongzheng Rd., Zhonghe Dist., New Taipei City 23586, Taiwan

□ should be <u>without</u> any modifications made

□ should be <u>with</u> some modifications made

to bring the EUT into compliance with the appropriate specifications (47CFR Part 15, Subpart B). If any, the details of the modifications including the complete descriptions, reasons and so on are described in next page of this report.

We , <u>Neousys Technology</u> hereby ensure that the product specified above will have all of the modifications incorporated in the product when manufactured and placed on the market.

The following importer or manufacturer is responsible for this statement:

Company Name	:	
Company Address	:	
Telephone	:	E-mail :
Legal Signature of	the i	responsible personal:

Title / Name (full name)

Date

The details of the modifications:

ltem	Solution Component	Specifications	Manufacturer	Quantity	Reasons
1					
2					
3					
4					
5				S	
6					-16-
7					
8			5	28-	
9			1/6	6	
10					
11					
12					
13					
14					
15					

If needed, some modification items are shown in the photographs in the following.